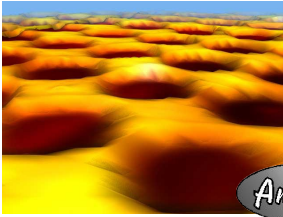


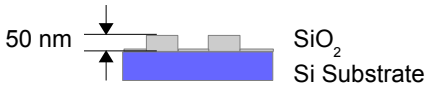
Height calibration grating UMG02B



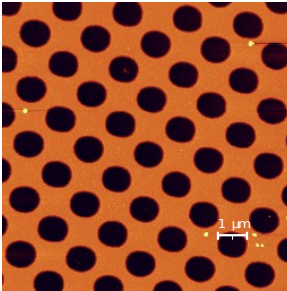
Anfatec Instruments AG
Tel.: 037421 24212, www.anfatec.de

Technical Data

Grating type	Si / SiO ₂
Height	50 +1/-3 nm
Chess Pitch	2 μm
Chess Area	1 mm x 1 mm
Line Pitch	4 μm
Line Length	500 μm



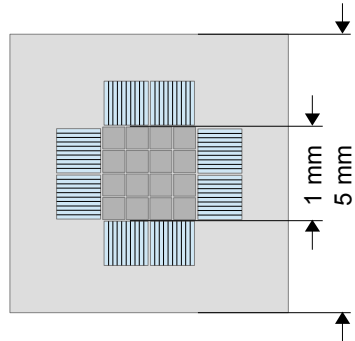
AFM Image - Topography



Typical Application

- Height calibration
- Lateral calibration

This grating has been developed for the height calibration as well as the lateral calibration.



Grating Structures

The active area of 1 mm x 1 mm is divided into 4 x 4 chess fields, each of them 250 μm by 250 μm large. The distance between the fields varies between zero and 7 μm. The structure is located in the centre of the sample and visible by eye. The edges around the holes are not 100% vertical, so that the height difference of 50 nm refers to the min-max height detectable.